

**Notice of References Cited**

Application/Control No.

09/778,172

Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

2128

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	M	US-			

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**NON-PATENT DOCUMENTS**

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	V	"Design of a diluted aperture by use of the practical cutoff frequency", J.L. Flores, Applied Optics, Vol. 38, No. 38, December 1999
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.